



Single Photon Technologies: Volume II

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Message from the Collection Editor

Dear Colleagues,

The topical collection "Single Photon Technologies: Volume II" intends to bring together a broad range of scientists and researchers with interests in single-photon sources, single-photon detectors, photon entanglement, and their use in scientific and industrial applications, to present the state of the art study in single photon technologies and applications.

This collection opens to all contributions (including original articles and reviews) related to the world of single photons. Papers are solicited in the following areas:

- Single-photon detectors: devices, circuits, and systems to achieve single-photon sensitivity;
- Single-photon sources: materials, schemes, and architectures to generate and control light emission at single photon level;
- Applications: single-photon technologies for scientific and industrial applications, from ground to space and from life science to quantum information processing;
- Metrology/validation techniques and instrumentation to prove single-photon generation and acquisition.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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